

IDS-10-02-2003

SHEET 1 OF 1

<b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b>  (PTO-1449)			ATTY. DOCKET NO. <b>60188-670</b>		SERIAL NO. <div style="font-size: 1.2em; font-family: cursive;">10/676877</div>					
			APPLICANT <b>Taiji NODA</b>							
			FILING DATE <b>October 02, 2003</b>		GROUP <div style="font-size: 1.2em; font-family: cursive;">2822</div>					
<b>U.S. PATENT DOCUMENTS</b>										
EXAMINER'S INITIALS	CITE NO.	Document Number <small>Number-Kind Codes (if known)</small>	Publication Date <small>MM-DD-YYYY</small>	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear					
MT	B1	US 6,432,802	08/13/2002	Noda et al.						
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<b>FOREIGN PATENT DOCUMENTS</b>										
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document <small>Country Codes-Number-Kind Codes (if known)</small>	Publication Date <small>MM-DD-YYYY</small>	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation				
MT		JP 8-250729	09/27/1996	ADVANCED MICRO DEVICES INC		<table border="1" style="width: 100%; border-collapse: collapse;"> <tr> <th style="width: 50%;">Yes</th> <th style="width: 50%;">No</th> </tr> <tr> <td>(Japan w/English Abstract)</td> <td style="text-align: center; font-size: 1.5em;">X</td> </tr> </table>	Yes	No	(Japan w/English Abstract)	X
		Yes	No							
		(Japan w/English Abstract)	X							
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>										
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.								
MT		Noda et al., "Effects of end-of-range dislocation loops on transient enhanced diffusion of indium implanted in silicon", JOURNAL OF APPLIED PHYSICS, PP.4980-4984, November 1, 2000.								
		T. Noda, "Modeling of End-of-Range (EOR) Defects for Indium Channel Engineering", Tech. Dig. IEDM, p.839, 2001								
EXAMINER <div style="font-size: 1.2em; font-family: cursive;">Michael Trim</div>				DATE CONSIDERED <div style="font-size: 1.2em; font-family: cursive;">5/23/05</div>						

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.